

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST
CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE)
CB SCHEME

SYSTEME CEI D'ACCEPTATION MUTUELLE DE
CERTIFICATS D'ESSAIS DES EQUIPEMENTS
ELECTRIQUES (IECEE) METHODE OC

CB TEST CERTIFICATE CERTIFICAT D'ESSAI OC

Product	Laboratory Equipment (microscope for IVD)
Name and address of the applicant	Leica Microsystems CMS GmbH Ernst-Leitz-Straße 17-37 35578 Wetzlar, GERMANY
Name and address of the manufacturer	Leica Microsystems CMS GmbH Ernst-Leitz-Straße 17-37, 35578 Wetzlar, GERMANY
Name and address of the factory	Leica Microsystems Ltd. Shanghai Building 1, 258 Jinzang Road, China (Shanghai) Pilot Free Trade, 201206 Shanghai, PEOPLE'S REPUBLIC OF CHINA
Ratings and principal characteristics	Rated voltage: 100-240 V Rated frequency: 50/60 Hz Rated power: 30 VA Protection class: I
Model/type Ref.	DM2000 LED 11888843
Additional information (if necessary)	Certificate DE 3 – 30073 issued 2015-09-08 is replaced by this version due to non technical changes
A sample of the product was tested and found to be in conformity with	IEC 61010-1:2010 IEC 61010-2-101:2015
as shown in the Test Report Ref. No. which forms part of this certificate	028-713133754-000

This CB Test Certificate is issued by the National Certification Body
Ce Certificat d'essai OC est établi par l'Organisme **National de Certification**

Date, 2018-05-22
CB 18 05 56257 178



Ralph Fischer



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Product Service